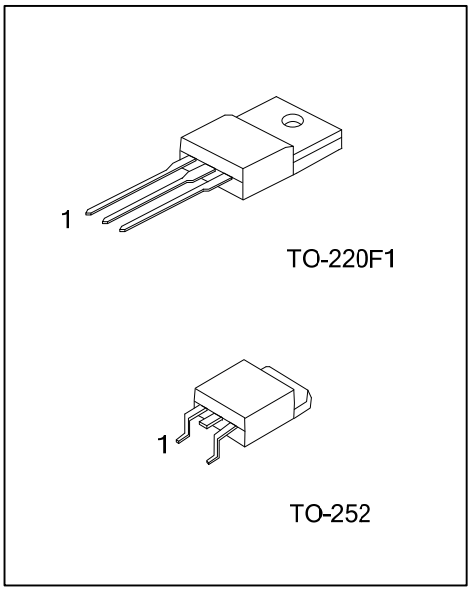
4A, 700V N-CHANNEL POWER MOSFET



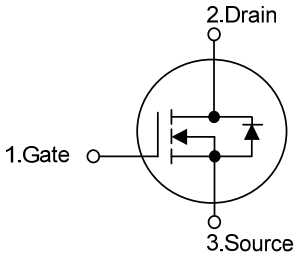
■ DESCRIPTION

The UTC **4N70-C** is a high voltage power MOSFET and is designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and high rugged avalanche. This high speed switching power MOSFET is usually used in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

■ FEATURES

* $R_{DS(ON)}$ < 2.8Ω @V_{GS} = 10 V
* Fast Switching Capability
* Avalanche Energy Specified
* Improved dv/dt Capability, High Ruggedness

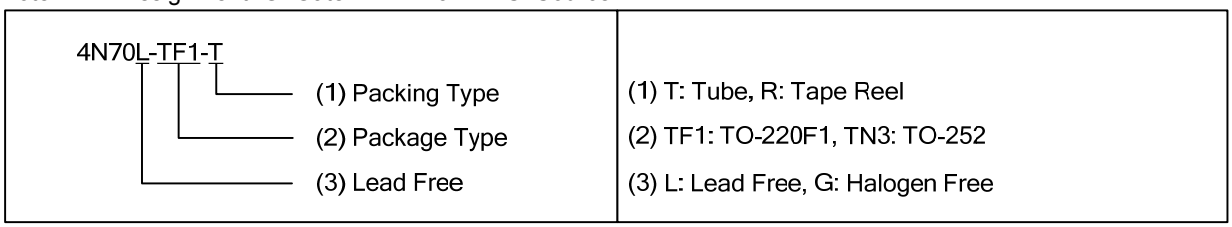
■ SYMBOL



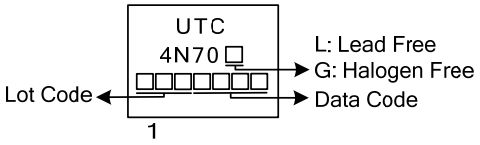
■ ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
4N70L-TF1-T	4N70G-TF1-T	TO-220F1	G	D	S	Tube
4N70L-TN3-R	4N70G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING INFORMATION

PACKAGE	MARKING
TO-220F1 TO-252	

■ ABSOLUTE MAXIMUM RATINGS (T_A = 25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	700	V
Gate-Source Voltage		V_{GSS}	±30	V
Avalanche Current (Note 2)		I_{AR}	4	A
Drain Current	Continuous	I_D	4	A
	Pulsed (Note 2)	I_{DM}	16	A
Avalanche Energy	Single Pulsed (Note 3)	E_{AS}	150	mJ
	Repetitive (Note 2)	E_{AR}	10.6	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation	TO-220F1	P_D	36	W
	TO-252		49	
Junction Temperature		T_J	+150	°C
Operating Temperature		T_{OPR}	-55 ~ +150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating : Pulse width limited by maximum junction temperature
3. L = 18.75mH, I_{AS} = 4A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C
4. I_{SD}≤ 4A, di/dt ≤200A/μs, V_{DD}≤ BV_{DSS}, Starting T_J = 25°C

■ THERMAL DATA

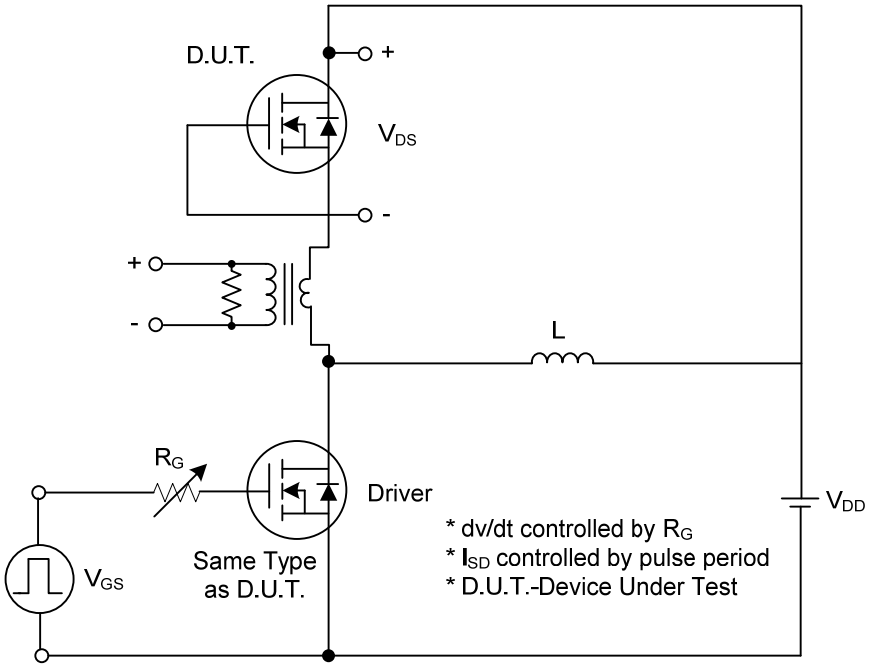
PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220F1	θ_{JA}	62.5	°C/W
	TO-252		110	
Junction to Case	TO-220F1	θ_{JC}	3.47	°C/W
	TO-252		2.55	

■ ELECTRICAL CHARACTERISTICS (T_A=25°C, unless otherwise specified)

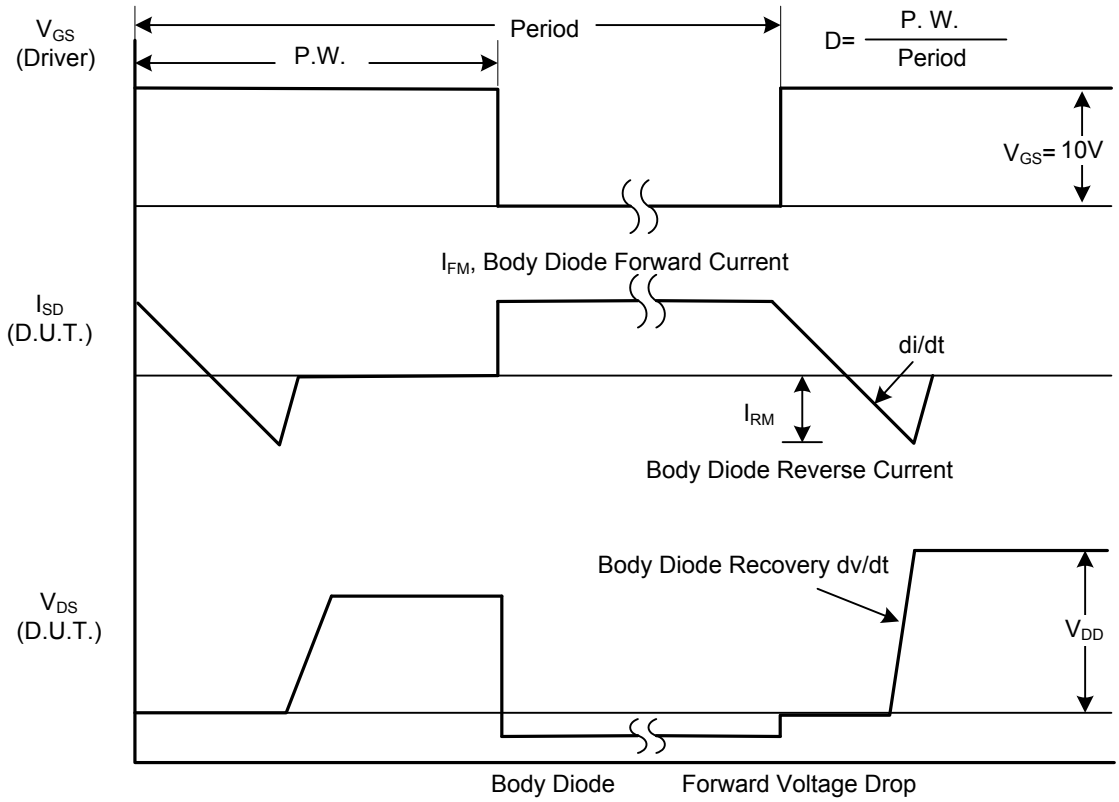
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	V_{GS} = 0 V, I_D = 250 μA	700			V
Drain-Source Leakage Current		I_{DSS}	V_{DS} = 700 V, V_{GS} = 0 V			10	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS} = 30 V, V_{DS} = 0 V			100	nA
	Reverse		V_{GS} = -30 V, V_{DS} = 0 V			-100	
Breakdown Voltage Temperature Coefficient		$\triangle BV_{DSS}/\triangle T_J$	I_D = 250μA, Referenced to 25°C		0.6		V/°C
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS} = V_{GS}, I_D = 250 μA	2.0		4.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS} = 10 V, I_D = 2A		2.6	2.8	Ω
DYNAMIC CHARACTERISTICS							
Input Capacitance		C_{ISS}	V_{DS} = 25 V, V_{GS} = 0 V, f = 1MHz		800	950	pF
Output Capacitance		C_{OSS}			320	400	pF
Reverse Transfer Capacitance		C_{RSS}			28	40	pF
SWITCHING CHARACTERISTICS							
Total Gate Charge		Q_G	V_{DS}= 50V, I_D= 1.3A, I_G= 100μA V_{GS}= 10 V (Note 1, 2)		16.5		nC
Gate-Source Charge		Q_{GS}			4.0		nC
Gate-Drain Charge		Q_{GD}			3.7		nC
Turn-On Delay Time		$t_{D(ON)}$	V_{DD} = 30V, I_D = 0.5A, R_G = 25Ω (Note 1, 2)		34	40	ns
Turn-On Rise Time		t_R			30	60	ns
Turn-Off Delay Time		$t_{D(OFF)}$			40	100	ns
Turn-Off Fall Time		t_F			39	70	ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Drain-Source Diode Forward Voltage		V_{SD}	V_{GS} = 0 V, I_S = 4A			1.4	V
Maximum Continuous Drain-Source Diode Forward Current		I_S				4	A
Maximum Pulsed Drain-Source Diode Forward Current		I_{SM}				16	A
Reverse Recovery Time		t_{rr}	V_{GS} = 0 V, I_S = 4A, dI/dt = 100 A/μs (Note 1)		250		ns
Reverse Recovery Charge		Q_{RR}			1.5		μC

Notes: 1. Pulse Test: Pulse width ≤ 300μs, Duty cycle ≤ 2%
2. Essentially independent of operating temperature

TEST CIRCUITS AND WAVEFORMS

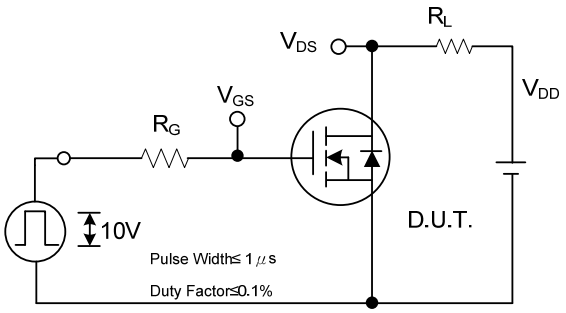


Peak Diode Recovery dv/dt Test Circuit

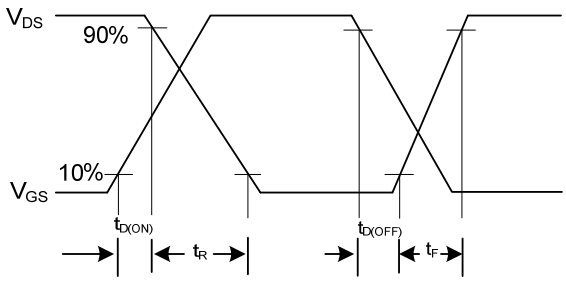


Peak Diode Recovery dv/dt Waveforms

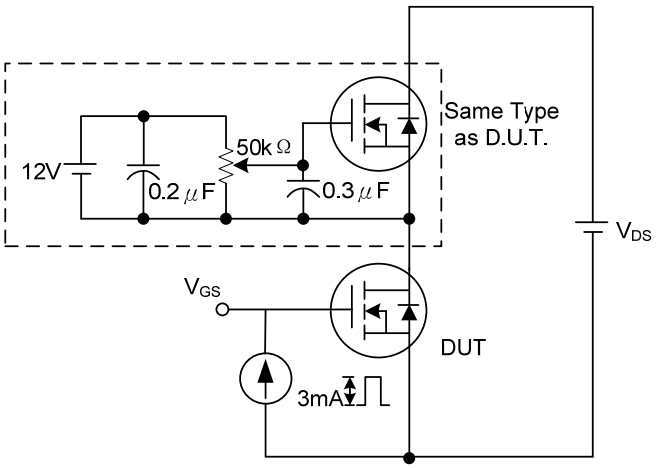
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



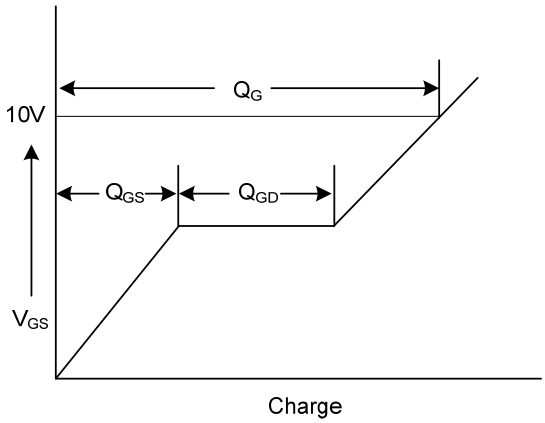
Switching Test Circuit



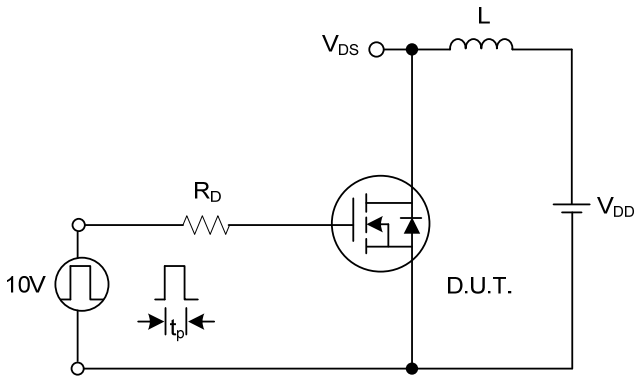
Switching Waveforms



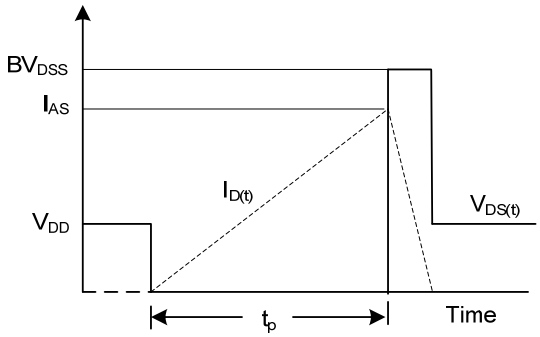
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms